A scattering experiment – wave picture



$$I = <|\sum_{j=1}^{N} \hat{A}_{j} e^{i(\mathbf{k_{f}} - \mathbf{k_{i}}) \cdot \mathbf{r_{j}}} e^{i\omega t}|^{2} >_{t} = |\int \rho(\mathbf{r}) e^{i\mathbf{Q} \cdot \mathbf{r}} \cdot \mathbf{dr}|^{2}$$

1. Linearity: The FT of $\rho(\vec{r}) = f(\vec{r}) + g(\vec{r})$ is

$$FT\left[f\left(\vec{r}\right) + g\left(\vec{r}\right)\right] = FT\left[f\left(\vec{r}\right)\right] + FT\left[g\left(\vec{r}\right)\right]$$

2. Convolution:

$$\rho\left(\vec{r}\right) = \int f\left(\vec{\xi}\right) g\left(\vec{r} - \vec{\xi}\right) d\vec{\xi}$$

Fourier Transform of the charge density distribution ρ from **R** space to-**Q** space

 $FT\left[f\left(\vec{r}\right) * g\left(\vec{r}\right)\right] = FT\left[f\left(\vec{r}\right)\right] \bullet FT\left[g\left(\vec{r}\right)\right]$

FT " converts" a convolution in a product and vice versa

T. Schulli, X-rays and reciprocal space







Intermezzo: few practical aspects of momentum space

Intermezzo: few practical aspects of momentum space



Concept of reciprocal space and practicality in experiments

- Makes it easy to compare different scattering experiments (this point is essential as Cu K-alpha wavelength is less and less a "world standard")
- Quick interpretation possible, peak width of harmonic peaks (110 220 330 etc.) can be extracted and interpreted (angular space is useless for peak width analysis)
- Quantity of Momentum Transfer best suited and most widely used is Å⁻¹, in diffraction, the SAXS community tends to use nm⁻¹. With the convenient definition of the wave-vector k= $2\pi/\lambda$, the momentum transfer Q results in Q=4 π *sin Θ/λ .
- This leads to the relation $Q_{hkl}=2 \pi/d_{hkl}$ linking momentum transfer to d-spacing of a certain reflection.
- When moving beyond structure determination (most cases you may work on), any high resolution analysis of a Bragg peak makes much more sense in reciprocal space than in angular space

Tobias Schulli AIBN Lecture Series

Size broadening and strain gradient broadening Strain may lead to lattice parameter gradients within one crystal. The resulting distribution Δd lattice parameter and its impact on the peak width ΔQ in reciprocal space Q can be obtained by looking at the first derivative of Q assuming a *d*-spacing change Δd :



Instrumental influences for peak broadening (examples)

Peak Broadening by spectral bandwidth $\Delta\lambda$

 $Q = \frac{4\pi s}{\lambda}, \quad -> \frac{\Delta Q}{\Delta \lambda} = -\frac{4\pi sin\theta}{\lambda^2} \rightarrow \Delta Q(\Delta \lambda) = \frac{4\pi sin\theta}{\lambda^2} \Delta \lambda = Q * \frac{\Delta \lambda}{\lambda},$ "equivalent" to strain broadening $\Delta \theta$: convergence angle

Peak Broadening by beam divergence $\Delta \Theta$:

$$Q = \frac{4\pi sin}{\lambda}, -> \frac{\Delta Q}{\Delta \theta} = \frac{4\pi cos\theta}{\lambda} ->$$

$$\Delta Q(\Delta \theta) = \Delta \theta \, \frac{4\pi \cos\theta}{\lambda} = \Delta \theta \, \frac{Q}{ta}$$

("Peak Broadening") as a function of Beam divergence $\Delta \theta$

Λθ

Tobias Schulli AIBN Lecture Series

Peak broadening, how to deal with

-it contains information that should be exploited -It teaches us to look at integrated intensities (Peak areas), rather than peak "heights"

Divergence: $\Delta Q(\Delta \theta) = \Delta \theta \frac{Q}{tan\theta}$ Bandpass: $\Delta Q(\Delta \lambda) = Q * \frac{\Delta \lambda}{\lambda}$ Strain: $\Delta Q(\Delta d) = \frac{\Delta d}{d} Q$ Size D : $\Delta Q(D) = \frac{2\pi}{D}$

FWHM (result)=

FWHM (curve1) + FWHM(curve2)....... $\sqrt{FWHM(curve1) + FWHM(curve2)}$ The truth is in general somewhere in between..... depends on the shape of the peaks

Tobias Schulli AIBN Lecture Series

All these contributions mix... in the form of convolutions

Peak broadening, how to deal with

-it contains information that should be exploited
-It teaches us to look at integrated intensities (Peak areas), rather than peak "heights"



For Q=0 only divergence and size contributions -> the minimum crystallite size can be estimated to be $D > \frac{2\pi}{0.002} \sim 3000 \text{ Å} (300 \text{ nm})$



Tobias Schulli AIBN Lecture Series

A bit more about Crystallite size D

Particle size (D) broadening:

 $\Delta Q(D) = \frac{2\pi}{D}$

No Q dependence If no other broadening effects are involved the size D can be extracted from any Bragg peak

A similar formula often cited is the Scherrer formula:

Hi...

In my today's tutorial, I will show you how to calculate crystallites size and average crystallites size from XRD data using Scherrer equation.

 $D = \frac{\kappa \lambda}{\beta \cos \theta} \tag{1}$

Where,

D = crystallites size (nm)

β=FW in rad

K = 0.9 (Scherrer constant)

 $\lambda = 0.15406$ nm (wavelength of the x-ray sources

Tobias Schulli AIBN Lecture Series

General remark: Be careful about what result you expect from particle size



What ever you extract, call it rather 200 nm instead of 218.67 nm However, if you stick to one method and compare different samples, relative differences may well be tracked down to few %



Examples for typical crystals and limits of these considerations for peak shapes

- As a start, we clearly have to differentiate between
- 1.)Powders
- 2.) (perfect) monocrystals
- 3.) Ideal imperfect crystals ("real" monocrystals) and perfect thin films

2.) Sounds easy but is the worst, so lets start with 3.) and the example of a thin film: goal: understanding peak *Intensities*

"Crystallography" = study of periodic objects

But in the end, what we are interested in may well be "the object"

A Crystal is an object associated with a regular (periodic or non-periodic) grating, defining its repetition





Scattering from an Crystalline thin block

Being a periodic arrangement of atoms a crystal can be "built" using a periodic arrangement of delta-functions convoluted with one atom (or a unit cell). A convolution in real space becomes a product in reciprocal space



Big crystals: sharp peaks, small crystals: narrow peaks. Peak intensities depend on the structure factor.

Diffraction from a thin film, simplified approach

We recall: The function describing intensity distribution in reciprocal space is related to the Fourier Transform of the distribution of scatterers in real space.

If we try to understand the building blocks of materials we can eventually treat their Fourier Transforms separately and use then these building blocks to built up reciprocal space.

What we are looking for is a set of lego pieces that we can decompose and recompose freely when moving from reciprocal space to real space



With reflection of X-ray light from the top and the bottom of a thin film there must also be a "Bragg-condition", but at very low angles of incidence, as the film thickness is "much thicker" than the spacing between atoms. Of course the path difference here as well can be 1,2, 3, ...,n, times λ . Leading to a series of tightly spaced peaks



At much lower angles than Bragg diffraction, there must be a "Bragg's law" for constructive interference from the top and the bottom of the thin film

[1] H. Kiessig (1931)"Interferenz von Röntgenstrahlen an dünnen Schichten". Annalen der Physik 10, 769-87.

X-ray reflectivity from a thin film

